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Alexander Stock

- ▲ Alexander earned his Masters in Electrical Engineering at the Technical University of Applied Sciences Aschaffenburg and his Doctorate in Engineering focused on Dynamic power measurements in electric motor drive applications.
- ▲ He recently joined HBK as a Technologist focused on Electric Power Testing.
- ▲ When he isn't in the lab, he enjoys traveling, endurance sports such as biking and jogging and cooking.



Understanding Measurement Uncertainty for Electric Drives

HBK WEBINAR

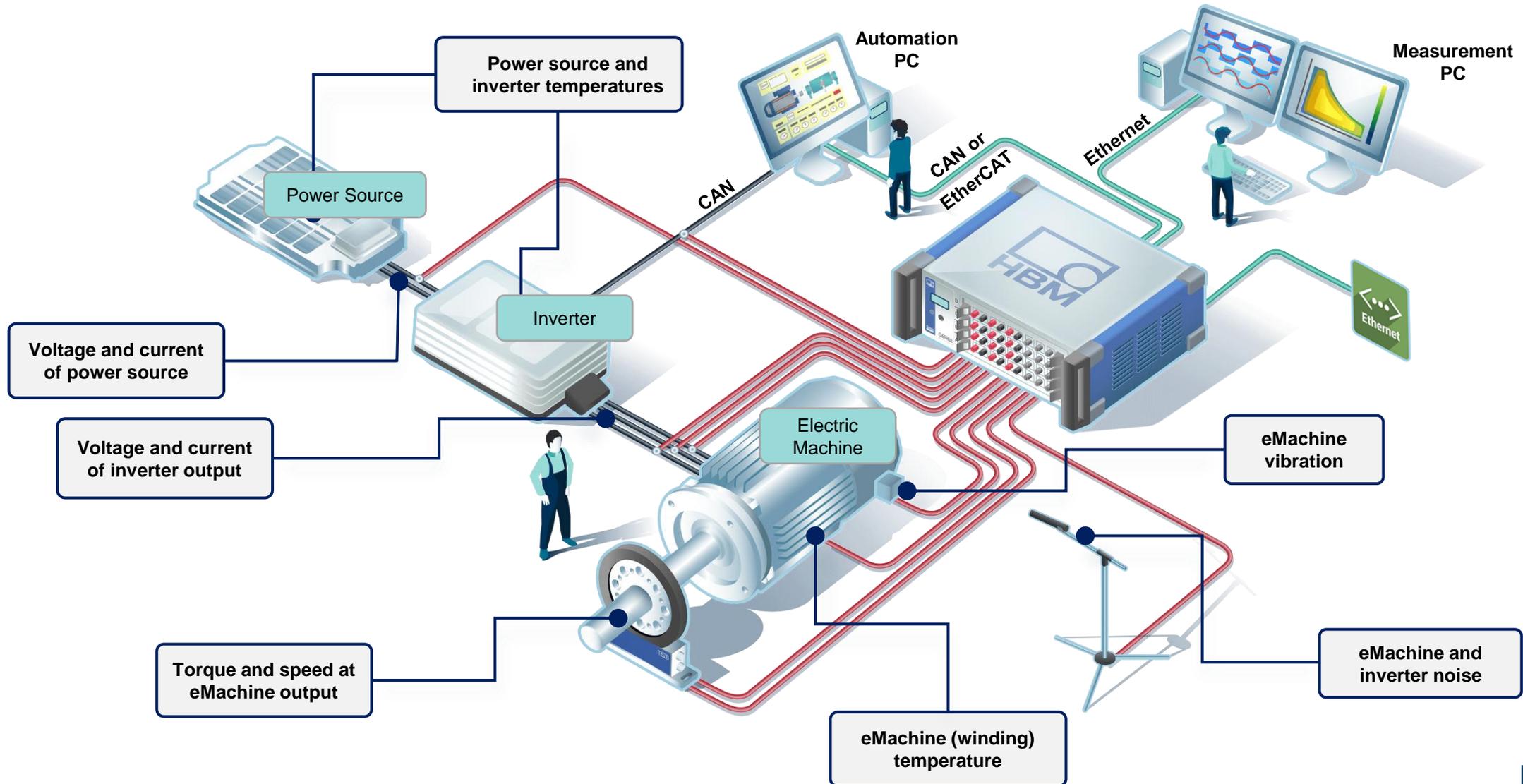
Dr.-Ing. Alexander Stock
08.03.2022



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1. Measurement on the electric drive train
2. Measurement uncertainty (MU)
3. Propagation of MU to resulting quantities
4. MU in dynamic measurement of electric power
5. Hardware based analysis of dynamic measurement uncertainty
6. Summary & Outlook

Measurement on electric drive train



Technical challenges measuring eDrive systems

Quasi-stationary drives (e.g., industrial drives, such as pumps or fans)



Highly dynamic drives (automotive, robotics)

Start-up process

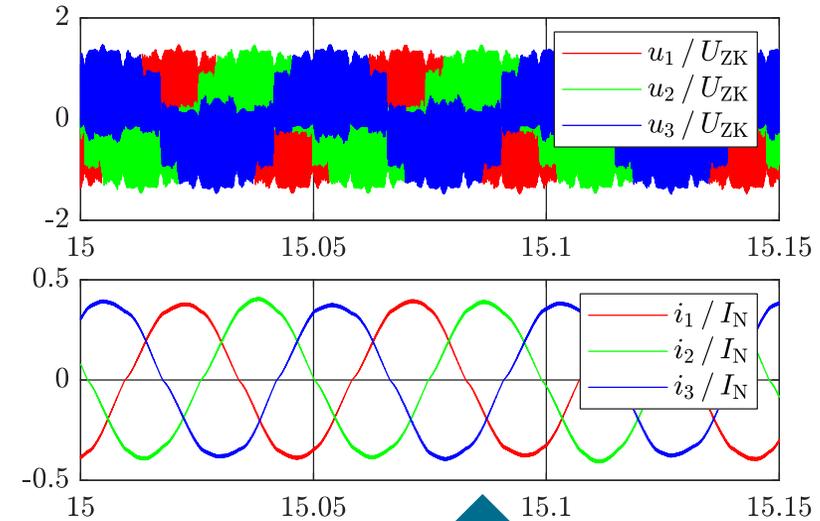


Fig. reference [4]

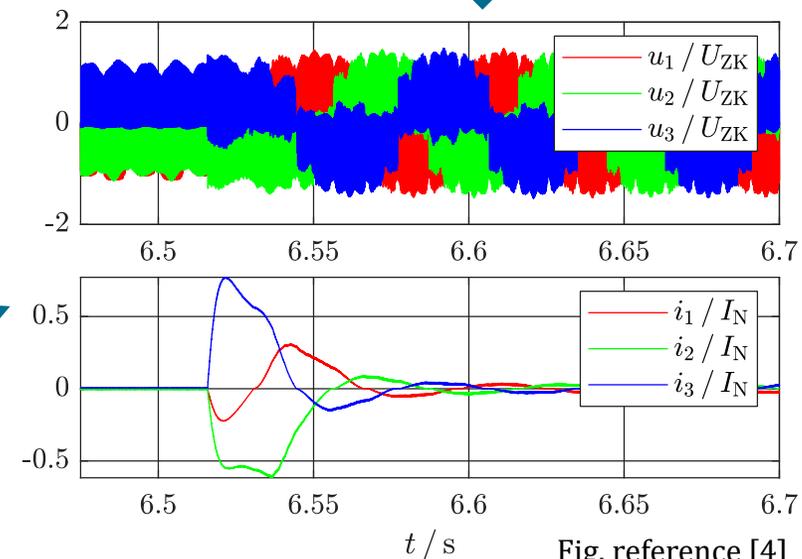


Fig. reference [4]

Statements on Measurement Uncertainty

GUM, section 3.1.2 (Basic Concepts):

„In general, the result of a measurement is only an approximation or estimate of the value of the measurand and thus is complete only when accompanied by a statement of the uncertainty of that estimate.“

Prof. Werner Richter (University of Leipzig):

Specifying a measurement result without indicating the measurement uncertainty is so uncertain that it is better not to specify at all.

Dave Packard:

"Measurements are always wrong - it's just a matter of how wrong."

Influence and effects of measurement uncertainty (MU)

MU in voltage
and current

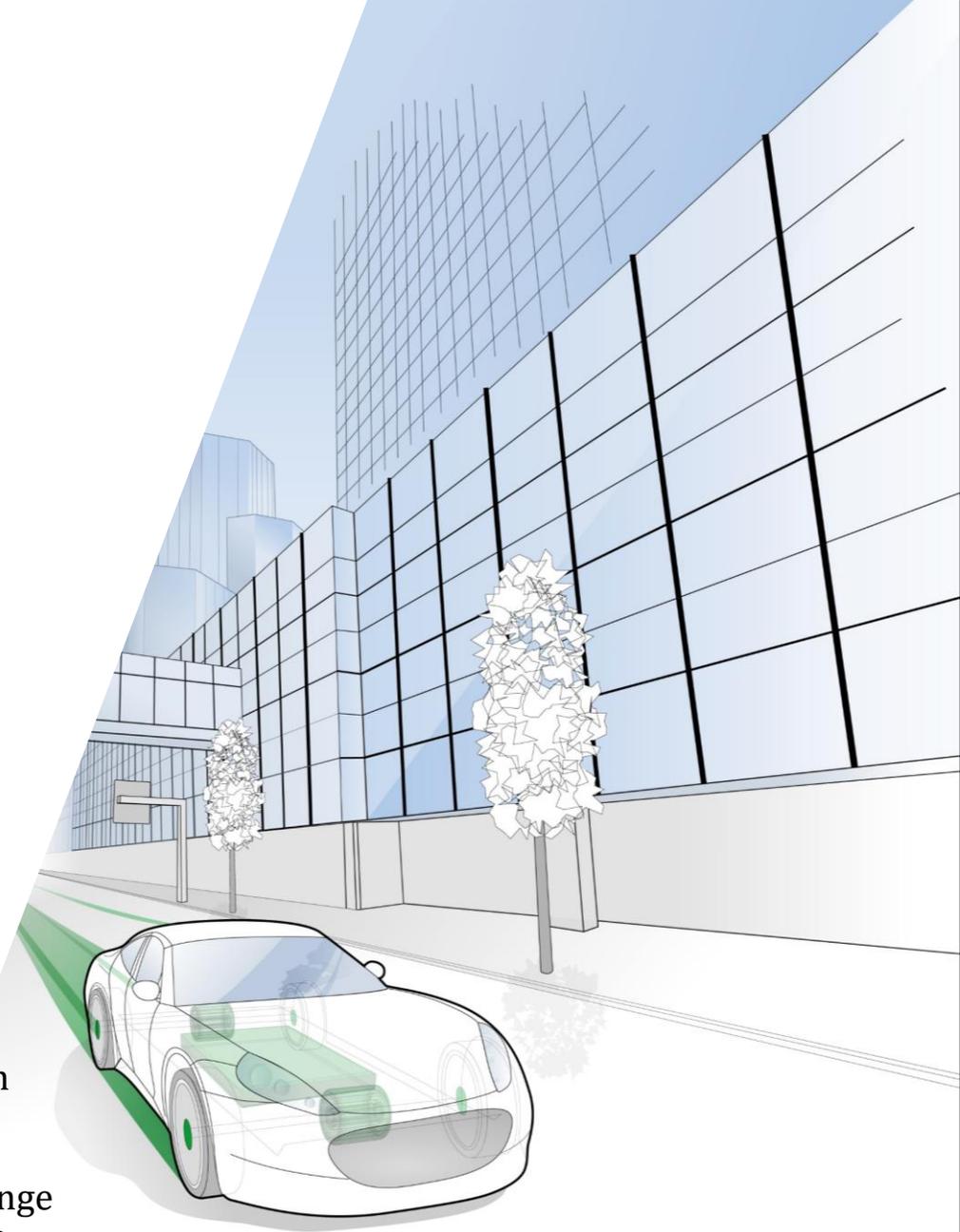
- All measurands are related to MU

MU in energy/power
→ efficiency

- MU propagates to calculated quantities

MU in vehicle
range

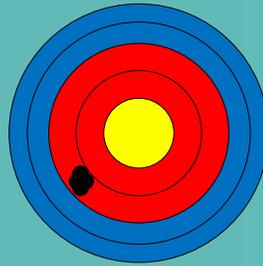
- Lower MU in voltage and current → higher range specification



Systematic and random error effects (influences)

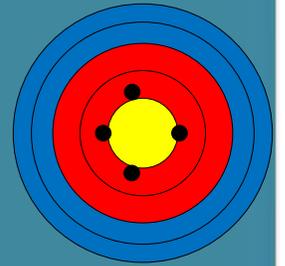
Systematic error effects [3,4]

- Reproducible under equal environmental conditions
- Generally avoidable by compensation (calibration)
- Examples:
incorrectly adjusted measuring device,
environmental conditions (temperature),
manufacturing tolerances leading to wrong
scaling/offset



Random error effects [3,4]

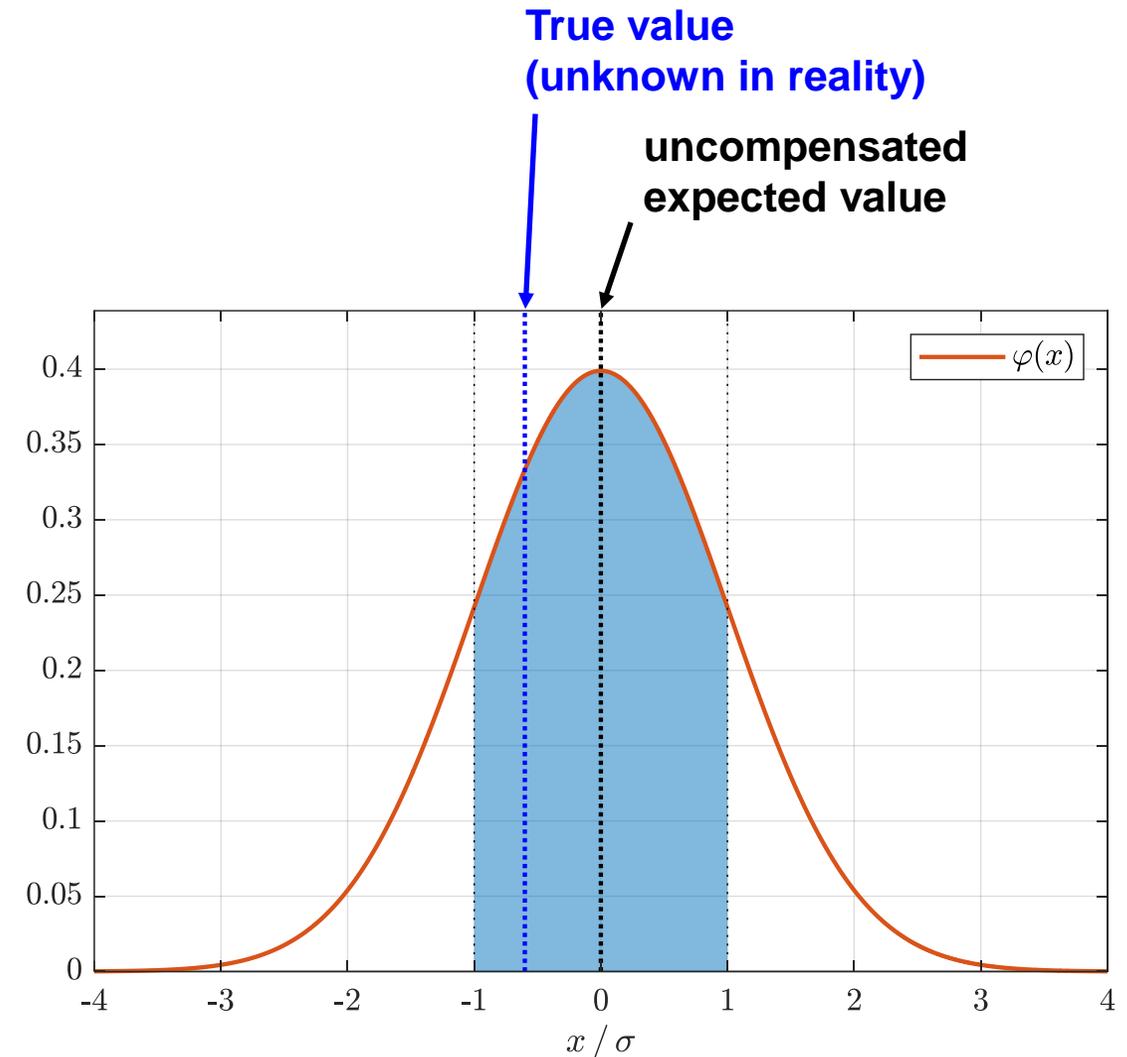
- Measured values scatter around the true value (even under the same ambient conditions and compensated systematic errors)
- Not reproducible → not compensable
- ("Real") randomness of quantum mechanical processes, e.g., thermal noise/resistive noise
- Apparently random but actually deterministic /deterministically chaotic processes whose source is only partially known or even completely unknown



→ Apparently random effects may be transferred to systematic effects through system knowledge improvement (more detailed model) [3,4].

Measurement Uncertainty (basic terms)

- ▲ Example: standard normal distribution
- ▲ Measurement uncertainty instead of measurement error (error is unknown because true value is unknown)
- ▲ Compensation of systematic effects
- ▲ Random effects result in MU represented by probability distribution
- ▲ After compensation of systematic influences, a measured value is in the interval of the specified MU of $\pm\sigma$ with a probability of 68.27%.
- ▲ References [1-3]



Error propagation

- Maximum measurement error of a variable y as a function of the variables $x_1 \dots x_n$ and their measurement errors $\Delta x_1 \dots \Delta x_n$ [2,3]:

$$\Delta y = \left| \frac{\partial y}{\partial x_1} \cdot \Delta x_1 \right| + \left| \frac{\partial y}{\partial x_2} \cdot \Delta x_2 \right| + \dots + \left| \frac{\partial y}{\partial x_n} \cdot \Delta x_n \right| = \sum_{k=1}^n \left| \frac{\partial y}{\partial x_k} \cdot \Delta x_k \right|$$

- Measurement uncertainty of a variable y as a function of the uncorrelated variables $x_1 \dots x_n$ and their uncertainties $\delta x_1 \dots \delta x_n$ (Gaussian error propagation) [2,3]:

$$\delta y = \sqrt{\left(\frac{\partial y}{\partial x_1} \cdot \delta x_1 \right)^2 + \left(\frac{\partial y}{\partial x_2} \cdot \delta x_2 \right)^2 + \dots + \left(\frac{\partial y}{\partial x_n} \cdot \delta x_n \right)^2} = \sqrt{\sum_{k=1}^n \left(\frac{\partial y}{\partial x_k} \cdot \delta x_k \right)^2}$$

Measurement uncertainty of DC power measurement (ideal)

- ▲ Measurement of the DC current I and the DC voltage U
- ▲ Calculation of the DC power (instantaneous power and active power are equivalent and constant)

$$P = U \cdot I$$

- ▲ Propagation of the measurement uncertainties of voltage and current to the measurement uncertainty of power

$$\delta P = \sqrt{\left(\frac{\partial P}{\partial U} \cdot \delta U\right)^2 + \left(\frac{\partial P}{\partial I} \cdot \delta I\right)^2} = \sqrt{(I \cdot \delta U)^2 + (U \cdot \delta I)^2} \quad (\text{Absolute MU})$$

$$\frac{\delta P}{P} = \sqrt{\left(\frac{\delta U}{U}\right)^2 + \left(\frac{\delta I}{I}\right)^2} \quad (\text{Relative MU})$$

Measurement uncertainty of power measurement (sinusoidal, ideal)

- ▲ Measurement of the sinusoidal AC current $i(t)$ and the sinusoidal AC voltage $u(t)$
- ▲ Calculation of the instantaneous power and the active power [5]

$$p(t) = u(t) \cdot i(t) \qquad P = \overline{p(t)}|_T = \frac{1}{T} \cdot \int_T p(t) dt = U \cdot I \cdot \cos(\varphi)$$

U, I : RMS values of voltage & current

φ : phase shift angle between voltage & current

- ▲ Measurement uncertainty of active power

$$\delta P = \delta P = \sqrt{\left(\frac{\partial P}{\partial U} \cdot \delta U\right)^2 + \left(\frac{\partial P}{\partial I} \cdot \delta I\right)^2 + \left(\frac{\partial P}{\partial \varphi} \cdot \delta \varphi\right)^2} = \sqrt{(I \cdot \cos(\varphi) \cdot \delta U)^2 + (U \cdot \cos(\varphi) \cdot \delta I)^2 + (U \cdot I \cdot \sin(\varphi) \cdot \delta \varphi)^2}$$

$$\frac{\delta P}{P} = \sqrt{\left(\frac{\delta U}{U}\right)^2 + \left(\frac{\delta I}{I}\right)^2 + (\tan(\varphi) \cdot \delta \varphi)^2} \quad (\text{Relative MU})$$

Measurement uncertainty of power measurement (arbitrary waveforms)

- ▲ Applying the Gaussian error propagation to $P = \frac{1}{T} \cdot \int_T p(t) dt$ is an analytical challenge 
- ▲ Practical implementation of active power calculation on measuring devices is discrete anyway

$$P = \frac{1}{N} \cdot \sum_{k=1}^N u_k \cdot i_k$$

- ▲ Max. Measurement error [4,6]: $\Delta P = \frac{1}{N} \cdot \sum_{k=1}^N |i_k \cdot \Delta u_k| + \frac{1}{N} \cdot \sum_{k=1}^N |u_k \cdot \Delta i_k|$

- ▲ MU [4,6]: $\delta P = \sqrt{\frac{1}{N^2} \cdot \left(\sum_{k=1}^N (i_k \cdot \delta u_k)^2 + \sum_{k=1}^N (u_k \cdot \delta i_k)^2 \right)}$

- ▲ Suitable method for dynamic processes/transients
- ▲ Bandwidth must be considered in addition to the error propagation when estimating the MU

Challenges in error propagation

- ▲ Each individual **active power value is calculated from N samples** of voltage & current $P = \frac{1}{N} \cdot \sum_{k=1}^N u_k \cdot i_k$
- ▲ **Each sample contains a certain MU**, which is then propagated to calculated quantities, such as active power
- ▲ **Systematic errors** (uncalibrated sensor) have the **same effect on every sample value** (e.g., manufacturing tolerances of circuit components of the input amplifier)
 - **Error is not reduced** by extending the averaging interval by means of **increasing the number of samples N** used for averaging
- ▲ **Random errors** (e.g., thermal noise) **can cancel out/neutralize** each other by averaging
 - Measurement errors are reduced by an increased number N of values used for averaging (ideal DC case: factor $1/\sqrt{N}$)
- ▲ **Interpretation and categorization of data sheet information**

Evaluation of data sheet information

- ▶ **MU of a quantity** (e.g., current) depends on the **MU of individual sensors** in the respective measuring chain (current transformer, burden resistor, measuring amplifier, etc.)
- ▶ **MU of each sensor** may depend on different, separately specified **influencing effects** (such as temperature, aging, etc.)
- ▶ **Individual influencing effects** are either specified in **absolute values, or relatively** with respect to the measured value or the full-scale value/measuring range
- ▶ The total measurement uncertainty of a measurand results from the squared superposition of the individual specifications:



$$\delta I = \sqrt{\underbrace{\sum_j (\delta I_{m,j} \cdot I)^2}_{\text{depending on the measured value}} + \underbrace{\sum_k (\delta I_{r,k} \cdot I_r)^2}_{\text{depending on the measuring range}} + \underbrace{\sum_l \delta I_{off,l}^2}_{\text{absolute offset}}}$$

(for sinusoidal quantities or DC quantities)

Specification Highlights		
Symbol	Value	Comment
Nominal primary AC current	I_{AC} 200 A RMS	
Nominal primary DC current	I_{DC} 300 A	
Nominal secondary current	I_{SC} 500 mA	At nominal primary DC current
Primary secondary ratio	$i_1 : i_2$ 1500	
Measurement range	I_{meas} 0-370 A	
Measurement resistance	R_m 3 Ohm max	See Figure 1.1 for details
Bandwidth	0-500 Hz	Small signal, refer to Figure 1.3

Electrical Specifications		
At $T_a = 25^\circ\text{C}$, supply voltage = +15 Volts		
Parameter	Symbol	Value
Character capacity	C_L	± 1500 A/r 0.1% (measured, 100 ms)
Linearity error	ϵ_L	± 2 ppm
Other current loading with burden	I_{load}	± 20 ppm
DC 10 Hz overall accuracy @ 25°C (1% full scale)	acc	± 22 ppm
Other temperature coefficient	TC_{meas}	± 0.3 ppm/K
Amplitude error	acc	$\pm 0.01\%$
Phase shift	acc	$\pm 0.05^\circ$
Response time to a step current @ 100% (0-100% full scale)	$t_{90\%}$	100 ns
Noise	σ	0-1 MHz: 0.1% 0-10 kHz: 0.04 ppm RMS 0-50 kHz: 0.02 ppm RMS
Phasor evaluation frequency	f_{eval}	50 Hz
Induced EMF voltage on primary conductor	V_{EMF}	2.5 mV/A
Stability		
Other stability over time	$\epsilon_{stability}$	± 0.2 ppm/month
Other change with initial external magnetic field	ϵ_{field}	± 2.2 ppm/Gauss
Other change with horizontal external magnetic field	ϵ_{field}	± 0.2 ppm/Gauss
Other change with power supply voltage change	$\epsilon_{V_{supply}}$	± 0.02 ppm/V
Other change with absolute power supply voltage tolerance	$\epsilon_{V_{supply}}$	± 0.02 ppm/V
Power supply		
Power supply voltage	V_{supply}	15 V ± 0.25 V DC
Positive current consumption	I_{pos}	100 mA ± 10 mA
Negative current consumption	I_{neg}	100 mA ± 10 mA

Measurement Uncertainty Tool

Ohne Titel - Perception (Primary) 8.29.21300.1151

Datei Bearbeiten Steuerung Automatisierung Fenster Arbeitsblätter Hilfe Genesis HighSpeed MU Calculation Tool

ePower Suite Genesis HighSpeed MU Calculation Tool

DC Power

Used Hardware
Module: GN310B

Ambient: 20 - 30 °C

Voltage
Methode: Only Module
Range: 500V

Current
Methode: Module & CT
Range: 0.6A
CT: HBM CTS200ID

Elapsed time since last calibration
CT1: 13 Month

Input Signals
U_{in}: 400.0 V
I_{in}: 180.0 A

Measurement Uncertainty

Calculate

P_{in}: 72 kW
Range of P_{in}: 150 kW
uncertainty u (absolute): 18.47 W
uncertainty w (relative): 0.03 %

AC Power

Used Hardware
Module: GN310B

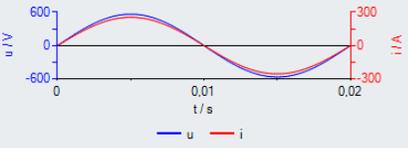
Ambient: 20 - 30 °C
Calculate: Single phase / Three phases

Voltage
Methode: Only Module
Range: 1000V

Current
Methode: Module & CT
Range: 0.15A
CT: HBM CTS400ID

Elapsed time since last calibration
CT1: 14 Month
CT2: Month
CT3: Month

Input Signals
U_{RMS}: 400.0 V
I_{RMS}: 180.0 A
f: 50.0 Hz
phi: 0 °



Measurement Uncertainty

Calculate

P: 72 kW
Range of P: 300 kW
uncertainty u (absolute): 35.60 W
uncertainty w (relative): 0.05 %

Mechanical Power

Used Hardware
Module: GN310B

Torque sensor with speed option
 Torque Sensor + Speed Sensor

Torque
Sensor: T40B
M_{nom}: 500Nm
Working range
Min: 50.0 Nm
Max: 400.0 Nm

Speed
Sensor: T40B
M_{nom}: 500Nm
Increments: 1024
Option: high speed ("H")
n_{nom}: 23000 RPM

Ambient: 20 - 30 °C
Frequency: 60 kHz

Influence of parasitic load:
 Approx. 10% of total budget
 Detailed calculation
Result: 10%

Input Signals
M: 400.0 Nm
n: 60.0 RPM
t_{meas}: 2.0 ms

Measurement Uncertainty

Calculate

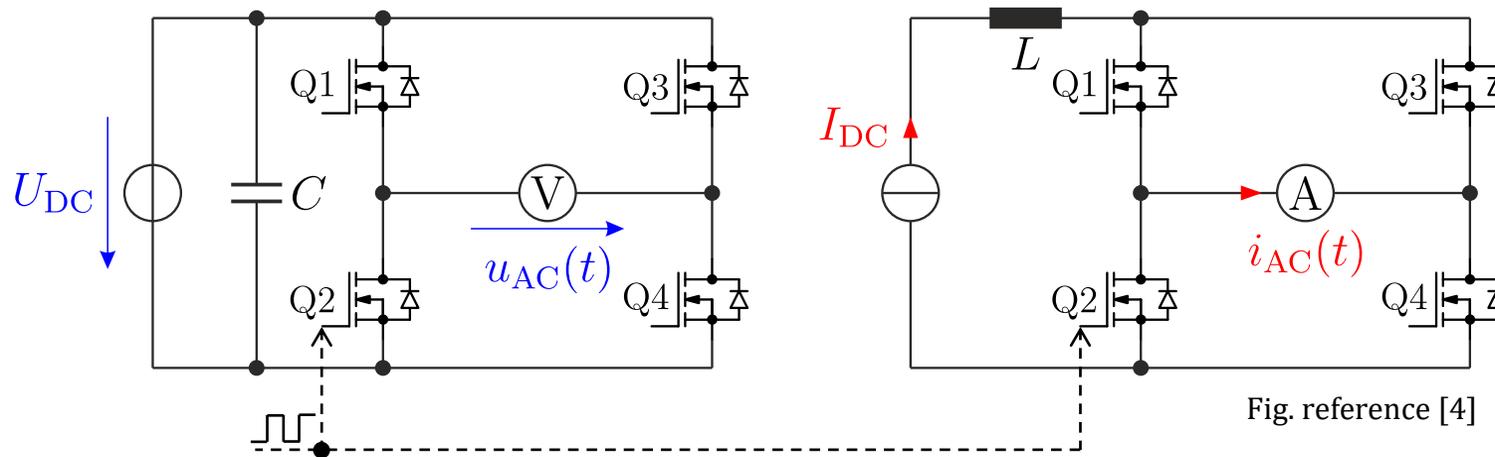
P_{mech}: 2.51 kW
Range of P_{mech}: 1.20 MW
uncertainty u (absolute): 2.20 W
uncertainty w (relative): 0.09 %
 Show detailed Measurement Uncertainty

V1.0 03 08 2021



Metrological analysis of the dynamic measurement uncertainty

- Design of two galvanically isolated full bridge circuits in SiC technology



cooperation with THAB
Prof. Dr.-Ing. Johannes Teigelkötter

Fig. reference [4]

- Synchronized control (PWM), maximum offset time of 25ns
- Generation of nearly ideal rectangular voltages and currents
- Calculation and comparison of "virtual" DC power and AC power ("virtual", since voltage and current are generated separately → the power does not physically occur)
- Without phase shift, DC and AC power are expected to be equal (ideal case)

Measurement of signals with oscilloscope

Switching time approx. 50 ns

→ Suitability for the comparison of power meters with typical sampling frequencies from 1 MHz to 10 MHz

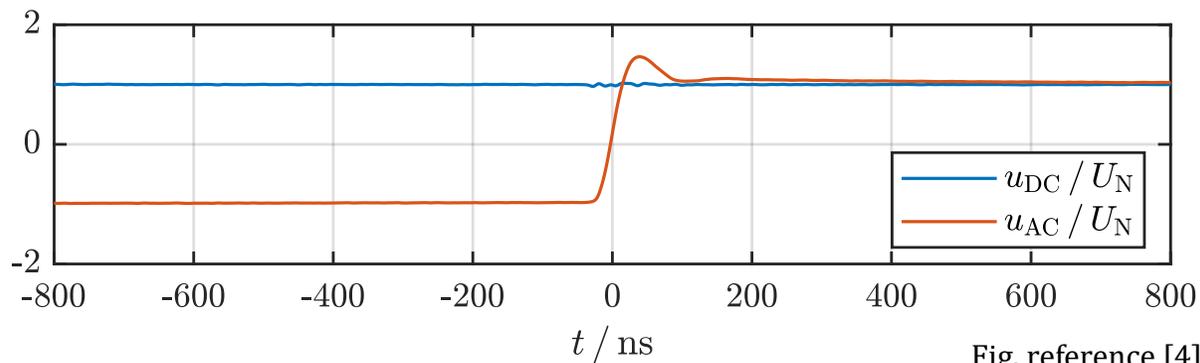
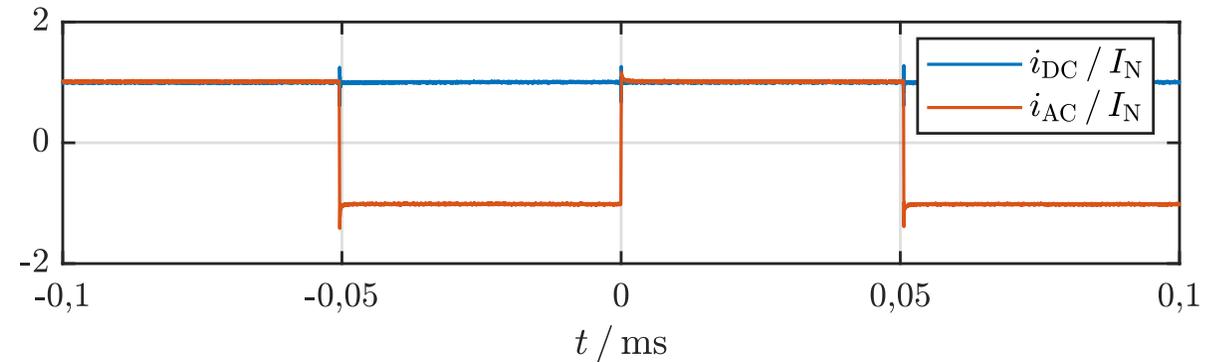
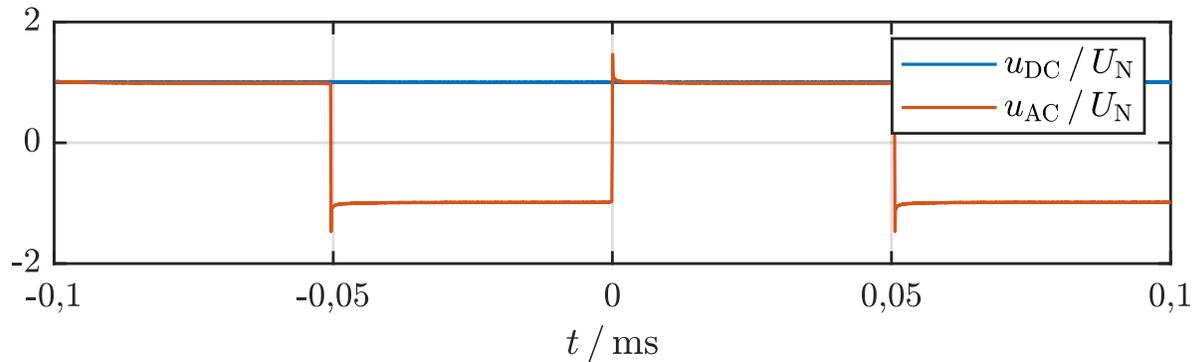


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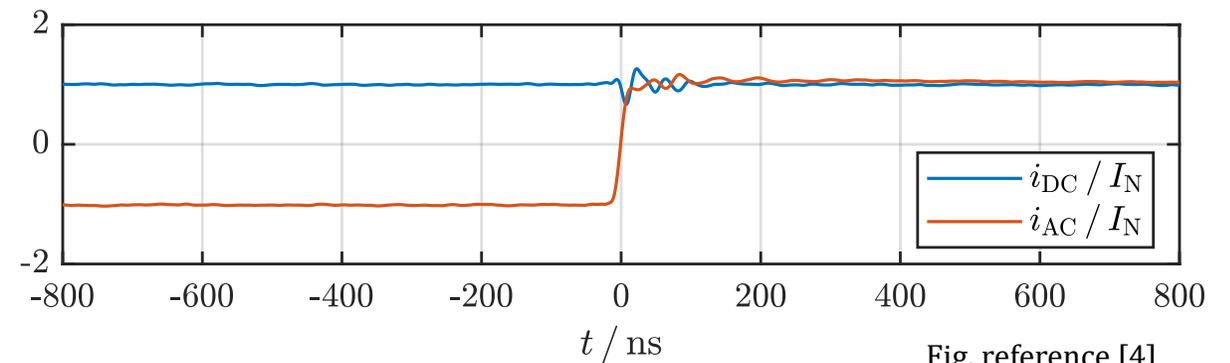


Fig. reference [4]

Summary

- ▲ Challenges in measurements on the powertrain
 - **time-synchronous** acquisition of **various physical quantities**
 - fundamental **cycle-based parameters** and **instantaneous values** (raw data)
- ▲ All **measured quantities** contain a certain **measurement uncertainty (MU)**
- ▲ **Analytical approach** of MU estimation for **DC quantities** and **sinusoidal** quantities well-known, see [1]
- ▲ **Analytical error propagation** approach for **arbitrary dynamic signals** is a challenge
→ solution based on discrete samples introduced
- ▲ **Hardware-based methods** for verifying the **dynamic measurement uncertainty**

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Thank You

Questions?
Please don't hesitate to contact me...

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